Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: **T0512-01** DATE: 12/23/05
Product Affected: IDT82V2088, IDT82V2084, IDT82V2048E IDT82V2044E on All Package Options
Date Effective: 03/22/06

MEANS OF DISTINGUISHING CHANGED DEVICES:
☐ Product Mark
☐ Back Mark
☒ Date Code Prefix (Stepping) change from "Y" to "YB"
☐ Other

Contact: Bimla Paul
Title: Quality Assurance Manager
Phone #: (408)-574-6419
Fax #: (408)-284-8362
E-mail: bimla.paul@idt.com

Attachment: ☒ Yes ☐ No
Samples: Available upon request

DESCRIPTION AND PURPOSE OF CHANGE:
☐ Die Technology
☐ Wafer Fabrication Process
☐ Assembly Process
☐ Equipment
☐ Material
☐ Testing
☐ Manufacturing Site
☐ Data Sheet
☒ Other

Product stepping changes from "Y" to "YB" to improve manufacturing efficiency. There is no change in data sheet parameters.

RELIABILITY/QUALIFICATION SUMMARY:
Please see the attachment for reliability data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:
IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: ____________________
☐ ***Approval for shipments prior to effective date.***
Name/Date: ____________________
E-Mail Address: ____________________
Title: ____________________
Phone# /Fax# : ____________________

CUSTOMER COMMENTS: ____________________

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY:
DATE:

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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT - PCN #: T0512-01

PCN Type: Product Stepping Change

Data Sheet Change: None

Detail of Change: Product stepping changes from "Y" to "YB" to improve manufacturing efficiency. There is no change in data sheet parameters.

Qualification Data: The following reliability tests were performed on 82V2088 DR208 (208-pin PQFP) Qualification results are as follow:

Test Description	Test Method	Required Sample/ # Fails	Test results
High Temperature Operating Life Test: Dynamic 1000 hrs @ 125°C	JESD22-A108	77/0	77/0
Highly Accelerated Stress Test (HAST): 130°C/ 85%R.H. Static Bias for 100 hours	EIA/JESD22-A100	45/0	45/0
Autoclave (Steam Pressure Pot), 168hrs @ 2 ATM, Saturated Steam @ 121°C	EIA/JESD22-A102	45/0	45/0
Temperature Cycle (T/C), -65°C/ 150°C for 500 cycles	JESD22-A104	45/0	45/0
ESD Human Body Model	Mil-Std 883 Method 3015	3/0	2,000V
ESD Charged Device Model	JEDEC 22-101	3/0	500V
Latch-up	EIA/JESD STD-78	10/0	10/0